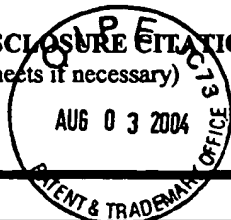


INFORMATION DISCLOSURE CITATION
(Use several sheets if necessary)



Docket Number (Optional)

BUR920030194US1 (17344)

Application Number

10/7/0642

Applicant(s)

James W. Adkisson, et al

Filing Date

7-27-04

Group Art Unit

2825
Unassigned

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

FOREIGN PATENT DOCUMENTS

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
hp		EP146661A1	12/16/86	EPO - ABSTRACT				

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

W		At-Speed Test Is Not Necessarlily An AC Test, by Jacob Savir and Robert Berry, Int'l Test Conf. 1991.
W		IBM Technical Disclosure Bulletin 8-86 P. 1234-1236, Measuring Process-Induced AC Chip Performance Variations Using SRLs.
W		IBM Technical Disclosure Bulletin 3-88 P. 288, Process Monitoring For LSSD Designs.

EXAMINER

[Signature]

DATE CONSIDERED

6/5/6

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

ELECTRONIC INFORMATION DISCLOSURE STATEMENT

Electronic Version v18

Stylesheet Version v18.0

Title of Invention

Designing Scan Chains With Specific Parameter Sensitivities to
Identify Process Defects

Application Number :

10/710,642

Confirmation Number:

First Named Applicant:

James Adkisson

Attorney Docket Number:

BUR920030194US1

Art Unit:

2825

Examiner:

GARBOWSKI

Search string:

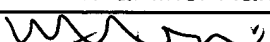
(4698830 or 5502731 or 5544173 or 5745405 or 5796751 or 6546514).pn

US Patent Documents

Note: Applicant is not required to submit a paper copy of cited US Patent Documents

init	Cite.No.	Patent No.	Date	Patentee	Kind	Class	Subclass
M	1	4698830	1987-10-06	Barzilai et al.			
M	2	5502731	1996-03-26	Meltzer			
M	3	5544173	1996-08-06	Meltzer			
M	4	5745405	1998-04-28	Chen et al.			
M	5	5796751	1998-08-18	Kundu			
M	6	6546514	2003-04-08	Hayem et al.			

Signature

Examiner Name	Date
	6/5/6